

[54] DATA PROCESSOR FOR MEASURING INSTRUMENTS

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[**] Term: 14 Years

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[58] Field of Search D10/46, 101, 103, 75, D10/78; D13/35, 4 C; D14/100, 107, 114; 324/72.5, 156, 114, 115

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[57] CLAIM

The ornamental design for a data processor for measuring instruments, as shown and described.

DESCRIPTION

FIG. 1 is a perspective view of a data processor for measuring instruments showing our new design;
FIG. 2 is a front elevational view thereof;
FIG. 3 is a rear elevational view thereof;
FIG. 4 is a top plan view thereof;
FIG. 5 is a bottom plan view thereof;
FIG. 6 is a left side elevational view thereof;
FIG. 7 is a right side elevational view thereof;
FIG. 8 is a sectional view taken on line 8—8 in FIG. 2; and
FIG. 9 is a sectional view taken on line 9—9 in FIG. 2.

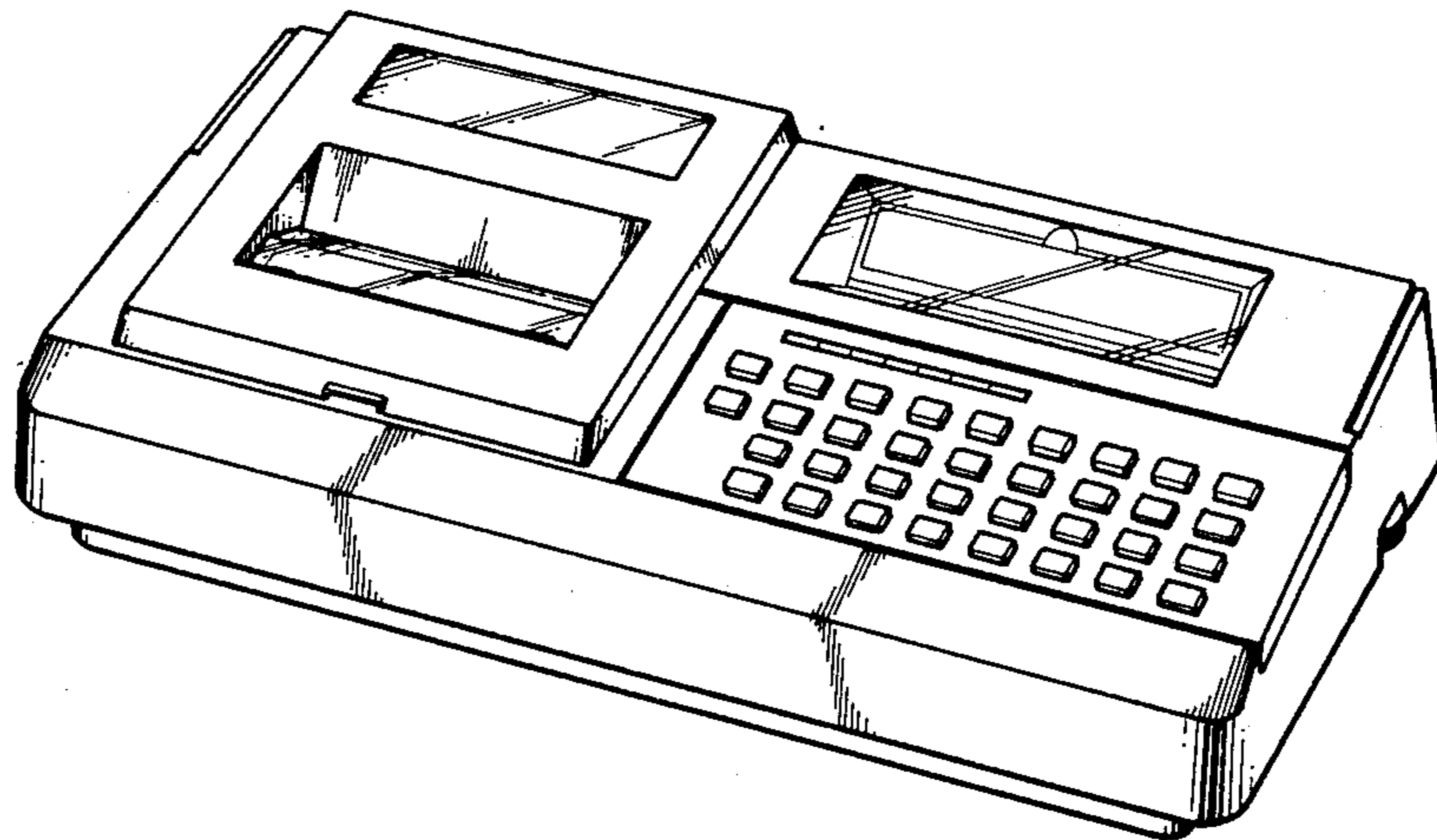


FIG. 1

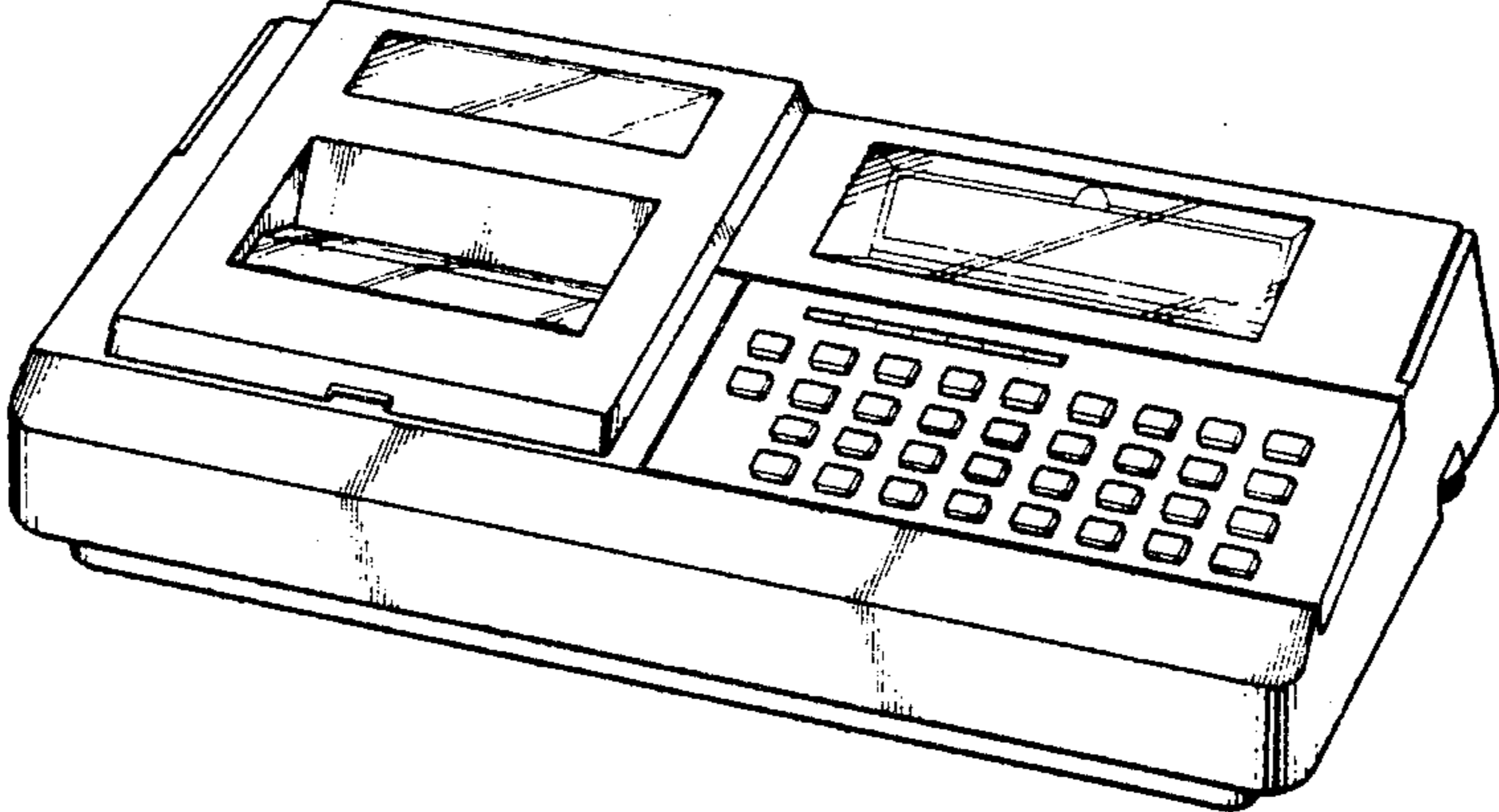


FIG. 2

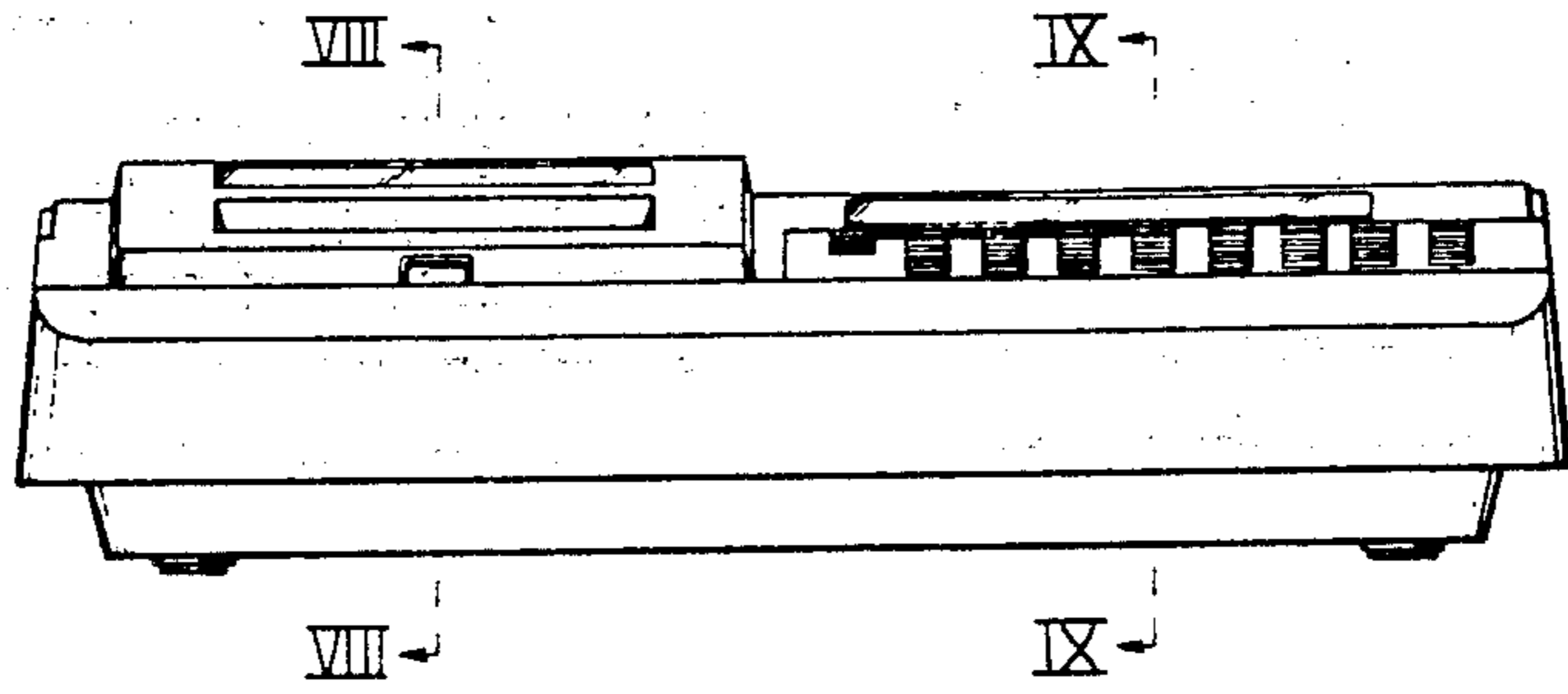


FIG. 3

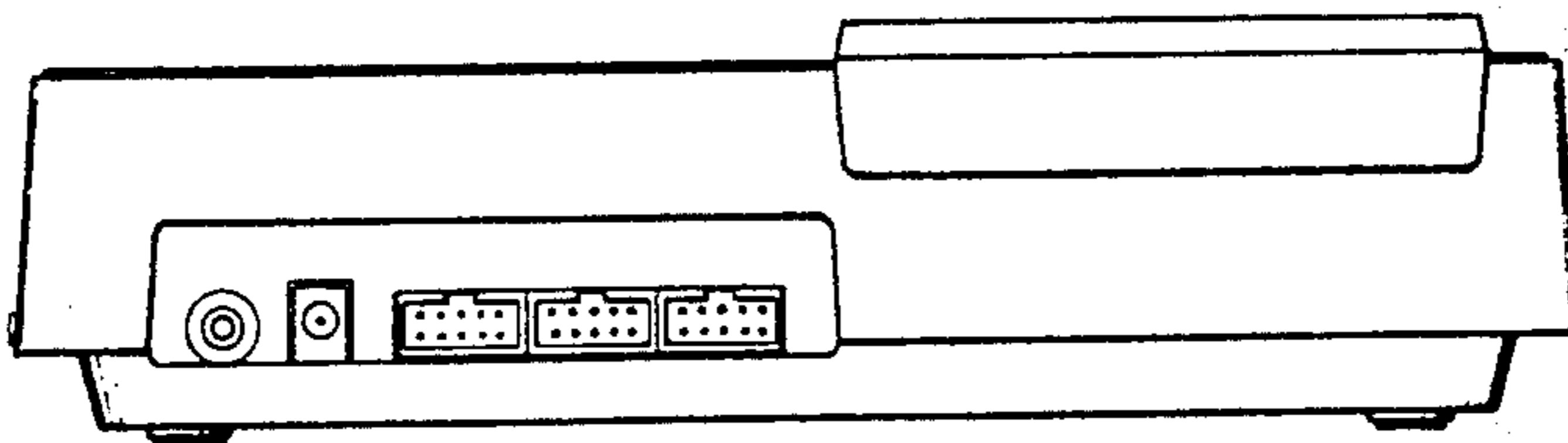


FIG. 4

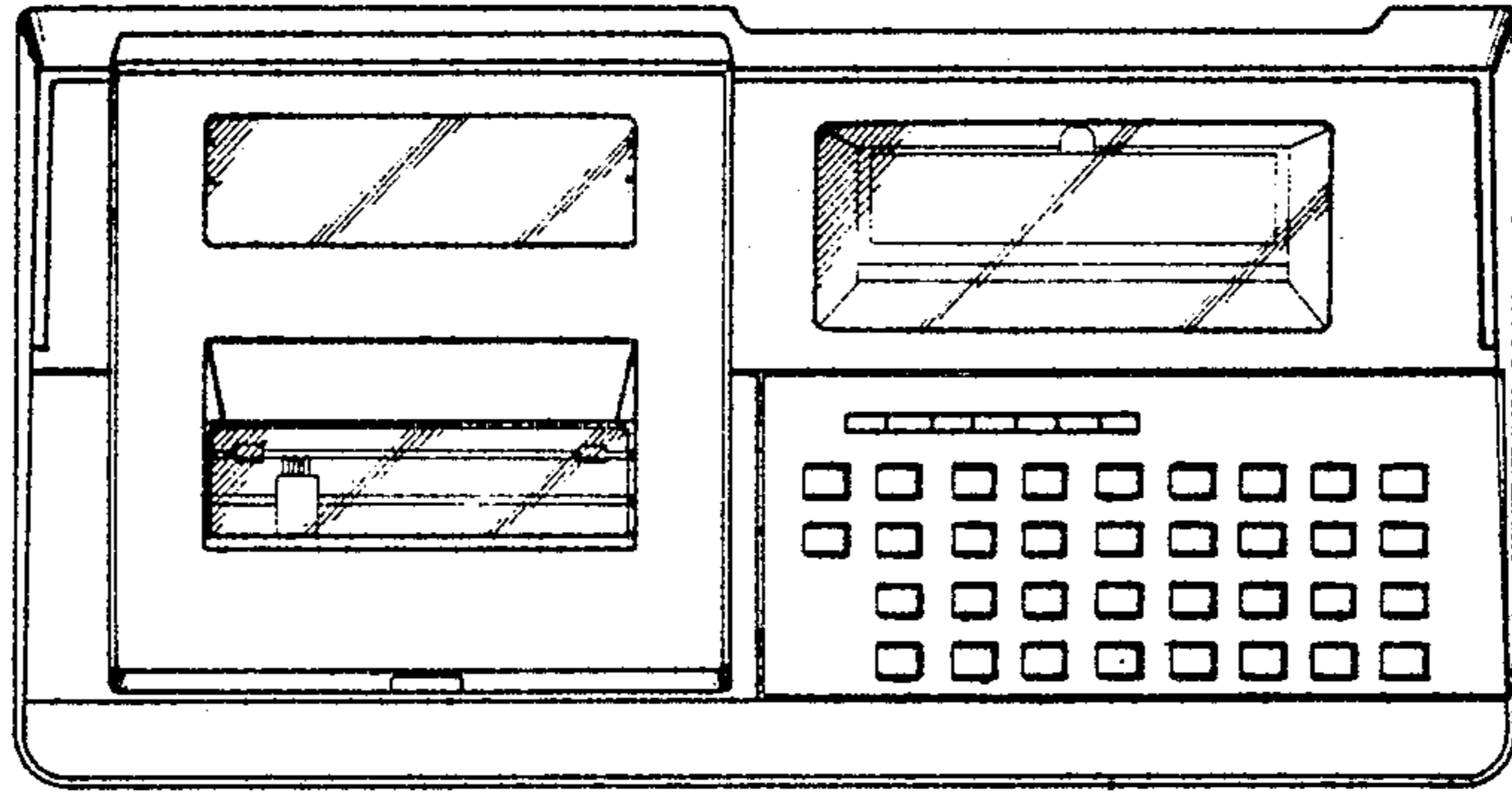


FIG. 5

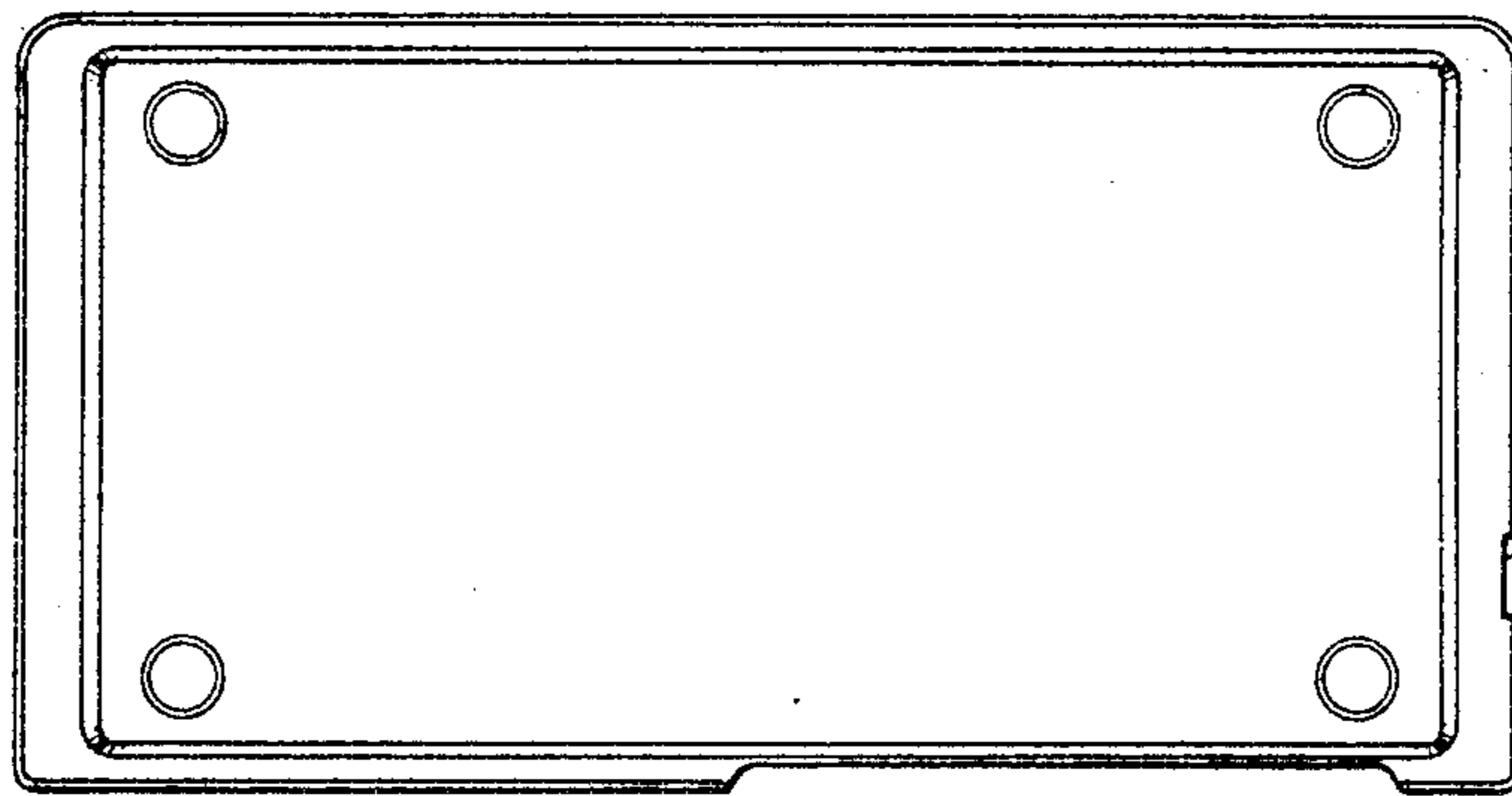


FIG. 6

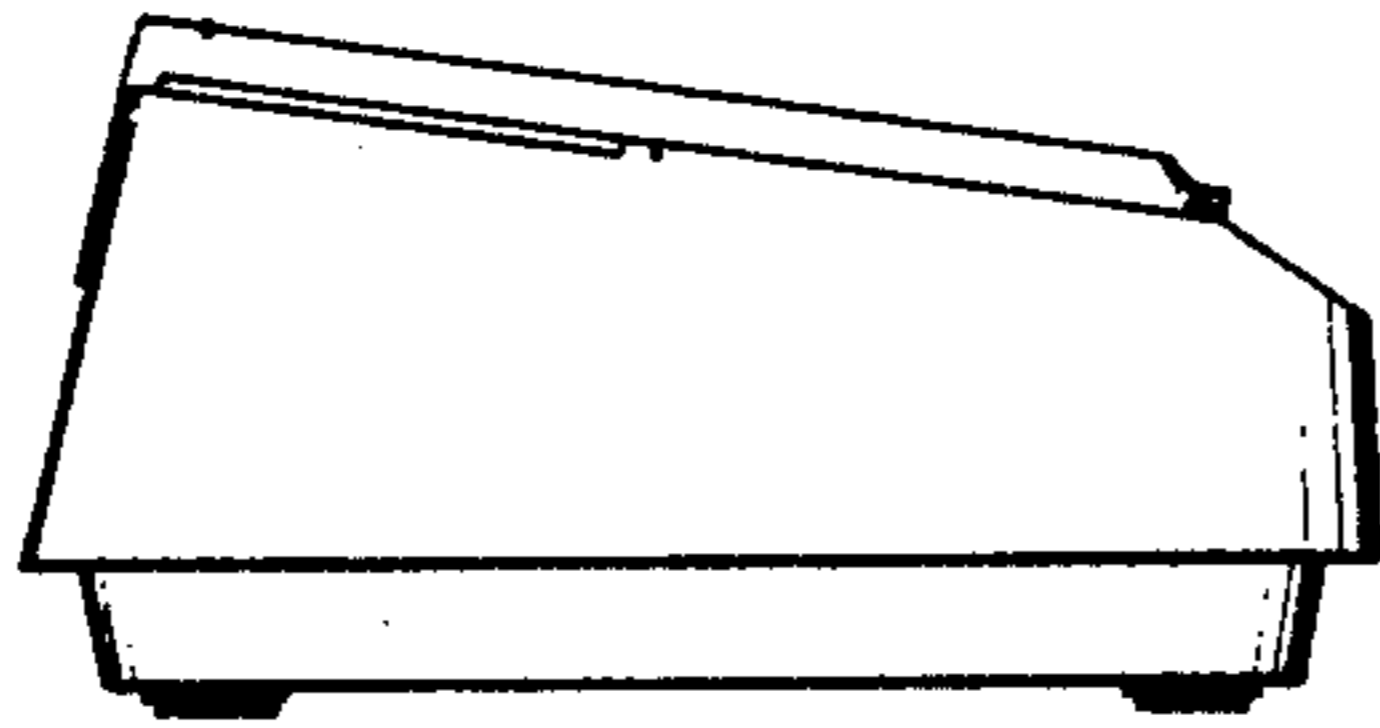


FIG. 7

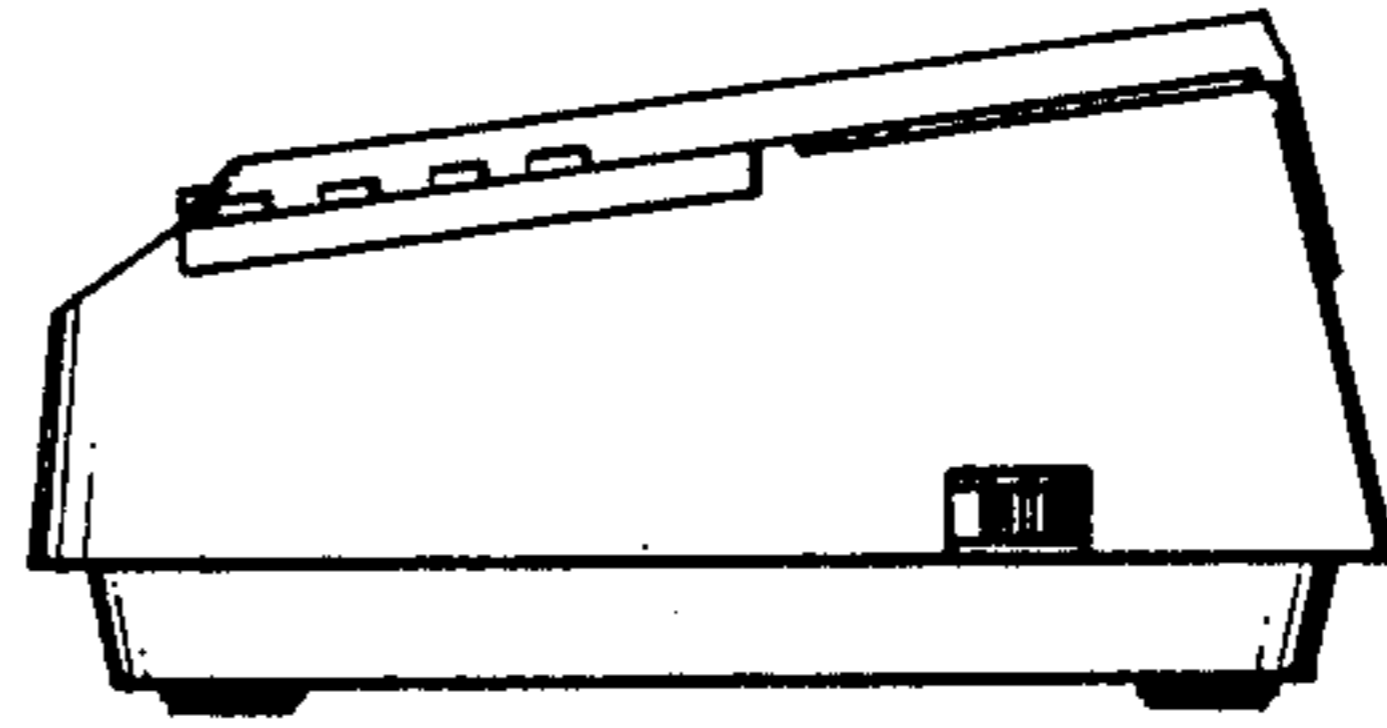


FIG. 8

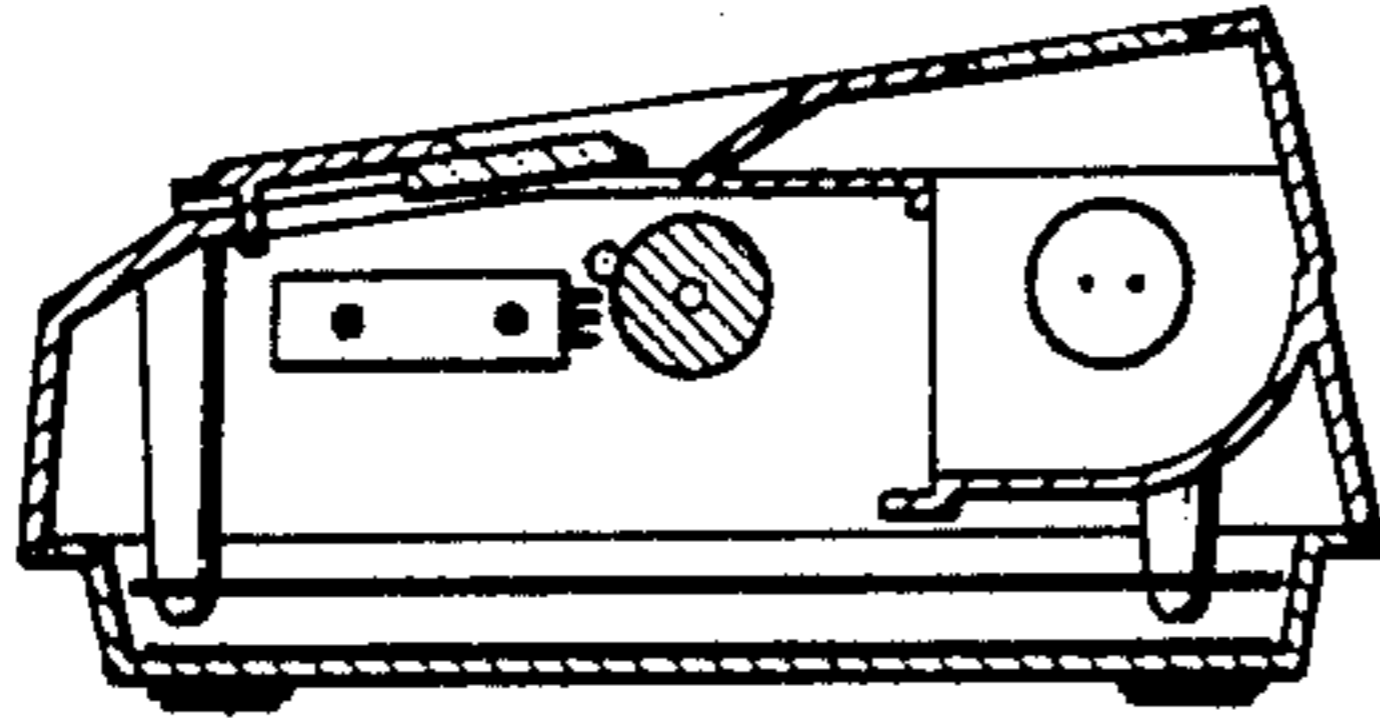


FIG. 9

